



# TestForum 2009

Scandic InfraCity, Stockholm, Sweden  
December 1<sup>st</sup> & 2<sup>nd</sup>, 2009

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Knut Båtstøløkken,  
Kitron

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MicroLEX Systems

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Nokia Siemens Networks

Jürgen Sedlacek,  
Alvetec KonTest

Tauno Jokinen,  
University of Oulu

## Test Forum 2009 Local Organizer

Jürgen Sedlacek  
Alvetec Kontest AB  
Phone: +46 8 626 40 57  
Fax: +46 8 754 88 67  
E-mail:  
jurgен.sedlacek@alvetekontest.se

## Partners of Nordic Test Forum



EXPERTKOMPETENS  
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## Call for Papers / Presentations

The 2 day TestForum 2009, the 10<sup>th</sup> event in the series, is a major event for Test professionals in the Nordic area and Baltic states. Every year the TestForum is attended by the industry's key persons as well as by international vendors of test and measurement equipment and solutions.

The event will take place at Scandic Infra City ([www.scandichotels.se/infracity](http://www.scandichotels.se/infracity)) 15 min from Arlanda Airport. Nordic Test Forum hereby cordially invites you to participate and submit your contribution to TestForum 2009, which includes (but is not limited to) the following topics:

- *Embedded Test*
- *Functional test*
- *AOI / AXI*
- *Test economics*
- *ICT / Flying Probe*
- *Boundary scan test*
- *Preventive test / Prognostics*
- *Best practices in manufacturing test*
- *ASIC: BIST / Mixed-signal / IDDQ / IDDT*
- *Board test SW, BIST, diagnostics*
- *Testing Lead Free Electronics*
- *Design to Test transfer / Design for Testing*
- *Data acquisition / collection / analysis*
- *Quality methods and tools*
- *ESD*
- *Test efficiency and optimization*
- *Future technology trends and test challenges*
- *Data acquisition / collection / analysis*

## Submissions

NTF seeks for full papers and/or presentations in the area of test of electronics, including *R&D, Application Contributions, Best Practices, Emerging Ideas*, etc. You are free to submit contributions outside the above topics as long as they stay within the field of electronics test. Focus shall be on new and upcoming challenges, opportunities and techniques rather than on particular products.

## Proceedings

At the event, Nordic Test Forum will deliver on electronic format the accepted contributions of authors that wish to provide the corresponding materials.

## The Format of the Event

- The event duration will be a two-day workshop and a small exhibition attached to it.
- November 30<sup>th</sup> on the evening there is the AGM of the NTF.
- The mix of presentations will decide the number of sessions.
- The presentations will be 30 minutes each: 25 minutes of speech and 5 minutes for questions and comments.
- During the exhibition, attendees will have a chance to see the latest equipment and talk to exhibitors.

## Key Dates

- Abstract submission:
- Notification of acceptance:
- Presentation slides:

**June 30<sup>th</sup>, 2009**

**August 31<sup>st</sup>, 2009**

**October 31<sup>st</sup>, 2009**

## Further Information and Submissions

Helle Stage  
MicroLEX Systems A/S  
Dr Neergaards vej 5C  
DK-2970 Hoersholm  
Phone: +45 4576 2100  
Email: hst@microlex.dk

Visit the NTF web pages at:

<http://www.nordictestforum.org>

